What is claimed is:

- 1. A system for screening micro-waviness of a disk having micro-waviness comprising the disk, a head comprising a detector, and a software or a hardware that measures a slope of an output of the detector versus a linear velocity of the disk or a fly height of the head.
 - 2. The system of claim 1, wherein the detector is a piezoelectric transducer.
 - 3. The system of claim 2, wherein the output is voltage.
- 4. The system of claim 1, wherein the output increases with an increase in the linear velocity or the fly height.
- 5. The system of claim 1, wherein the output substantially correlates with a micro-waviness of a disk measured by an optical surface topography metrology tool.
- 6. The system of claim 1, wherein the head is calibrated against a standard head.
 - 7. The system of claim 1, wherein the disk is a magnetic recording disk.
- 8. The system of claim 1, wherein the detector picks up disk micro-waviness induced air-bearing resonance.

- 9. The system of claim 1, wherein the disk comprises asperities and waviness.
- 10. A system for measuring micro-waviness of a disk having micro-waviness comprising the disk, a head comprising a detector, and means for measuring a slope of an output of the detector versus a linear velocity of the disk or a fly height of the head.
- 11. A method for screening a disk having micro-waviness comprising detecting air bearing resonance by a detector in a head, and measuring a slope of an output of the detector versus a linear velocity of the disk or a fly height of the head.
- 12. The method of claim 11, further comprising measuring micro-waviness of the disk.
 - 13. The method of claim 11, wherein the detector is a piezoelectric transducer.
 - 14. The method of claim 13, wherein the output is voltage.
- 15. The method of claim 11, wherein the output increases with an increase in the linear velocity or the fly height.

- 16. The method of claim 11, wherein the output substantially correlates with a micro-waviness of a disk measured by an optical surface topography metrology tool.
- 17. The method of claim 11, wherein the head is calibrated against a standard head.
 - 18. The method of claim 11, wherein the disk is a magnetic recording disk.
- 19. The method of claim 11, wherein the disk comprises asperities and waviness.